

## **Quarterly Reliability Monitoring Results**

## Quarters: Q1/2022 to Q4/2023

Based on structural similarity

| Supplier Nexperia B.V. Name of Laboratory Assembly reliability labs |  | User Part Number  |                                   |           |            |           |  |  |
|---|--|---|-----------------------------------|-----------|------------|-----------|--|--|
|   |  | PESD48VV2BT   |                                   |           |            |           |  |  |
|   |  | Part Description  |                                   |           |            |           |  |  |
|   |  | Nexperia DHAM Protection Bipolar  |                                   |           |            |           |  |  |
|   |  | SMD package   |                                   |           |            |           |  |  |
| Test  |  | Test Conditions   | Duration                          | # Lots    | # Quantity | # Rejects |  |  |
|   | <b>TEST</b> Pre- and Post-Stress                         |   |                                   |           |            |           |  |  |
| # 1   | Electrical Test  | Tamb = 25 °C  | N/A                               | see below | all parts  | see below |  |  |
| # 2   | <b>PC</b> Preconditioning                                | JESD22-A113 Bake Tamb = 125 °C Soak Tamb = 85 °C, RH = 85% Reflow soldering                         | 24 hours<br>168 hours<br>3 cycles | 524       | 22940      | 0         |  |  |
| # 5   | HTRB<br>High Temperature Reverse<br>Bias                 | MIL-STD-750-1<br>M1038 Method A<br>Tj = Tjmax, Vr = 100% of max. datasheet<br>reverse voltage       | 1000 hours                        | 45        | 2000       | 0         |  |  |
| # 7   | <b>TC</b><br>Temperature Cycling                         | JESD22-A104<br>-65 °C to Tjmax, not to exceed 150°C   | 1000 cycles                       | 156       | 7080       | 0         |  |  |
| # 8 <b>or</b>   | <b>UHAST</b><br>Unbiased HAST                            | JESD22-A118<br>Tamb = 130 °C, RH = 85 %   | — 96 hours                        | 156       | 7080       | 0         |  |  |
| # 8a  | <b>AC</b><br>Autoclave                                   | JESD22-A102<br>Tamb = 121 °C, RH = 100 %<br>Pressure = 205 kPa (29.7 psia)                          |                                   |           |            |           |  |  |
| # 9   | <b>H3TRB</b> High Humidity High Temperature Reverse Bias | JESD22-A101 Tamb = $85$ °C, RH = $85$ %, VR = $80$ % of rated reverse voltage <sup>[1]</sup>        | 1000 hours                        | 156       | 7080       | 0         |  |  |
| # 10  | <b>IOL</b> Intermittent Operating Life                   | MIL-STD-750 Method 1037 ton = toff, devices powered to insure $\Delta Tj = 100$ °C for 15000 cycles | 1000 hours                        | n.a.      | n.a.       | n.a.      |  |  |
| # 20  |  | JESD22-A111<br>260 °C ± 5 °C  | 10 s                              | 56        | 1700       | 0         |  |  |
| # 21  | <b>SD</b><br>Solderability                               | J-STD-002   |                                   | 56        | 1700       | 0         |  |  |

<sup>[1]</sup> The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

## **Calculation of FIT and MTTF**

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test # 5) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

| Wafer Fab | Technology         | Quantity | Rejects | Failure Rate (FIT) | MTTF (hrs) |
|-----------|--------------------|----------|---------|--------------------|------------|
| Nexperia  |                    |          |         |                    |            |
| DHAM      | Protection Bipolar | 2000     | 0       | 2,12               | 4,71E+08   |

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